Microwave Measurements of GaAs Integrated Circuits Using Electrooptic Sampling

K.J. Weingarten, R. Majidi-Ahy, M.J.W. Rodwell, B.A. Auld and D.M. Bloom. "Microwave Measurements of GaAs Integrated Circuits Using Electrooptic Sampling." 1987 MTT-S International Microwave Symposium Digest 87.2 (1987 Vol. II [MWSYM]): 877-880.

We describe the electrooptic sampling system at Stanford with emphasis on the requirements for microwave measurements. Results presented include internal-node measurements of 20 GHz distributed amplifiers, propagation delays in GaAs frequency dividers clocked to 18 GHz, and VSWR on IC transmission lines to 40 GHz.

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